

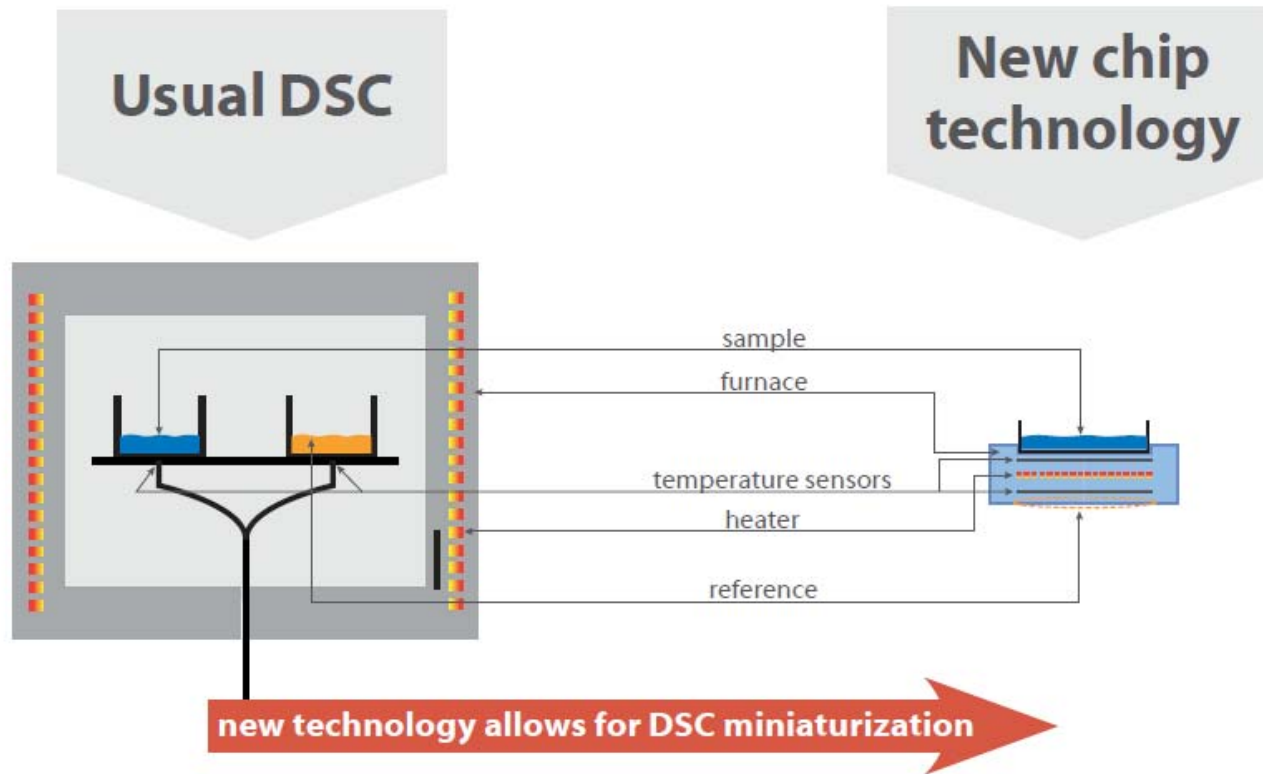
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Chip DSC- Miniaturized Calorimeter with integrated heater, temperature sensors and crucible

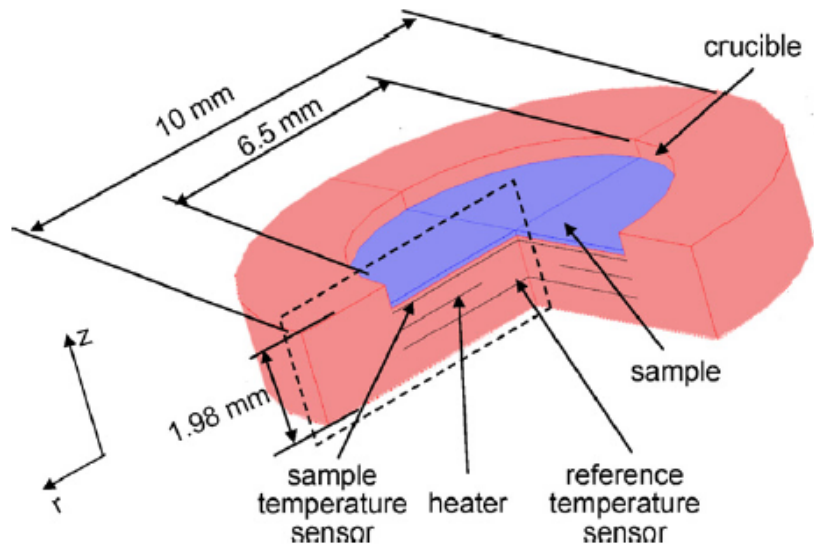
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Basic Concept



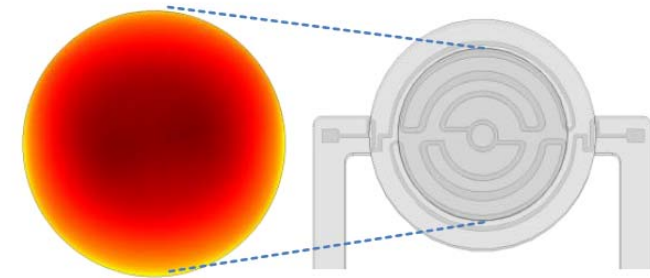
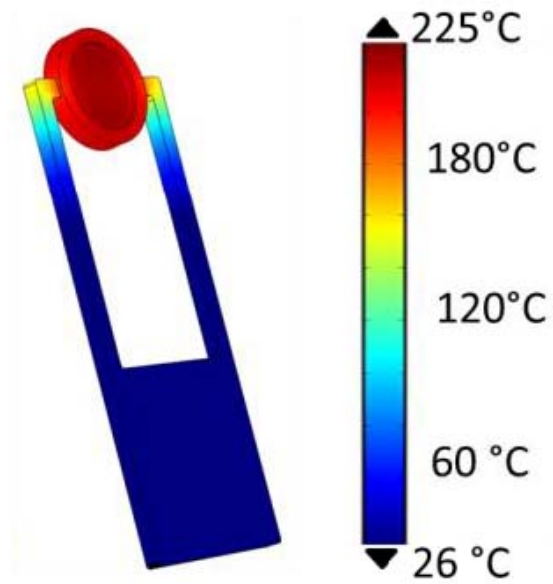
Chip DSC Sensor



Includes all components of a classical Heat Flux DSC:

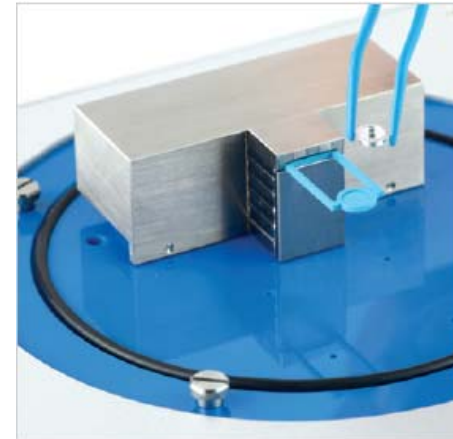
- Heater
- Sample and Reference temperature sensor
- Crucible

Optimized Chip Design



Uniform Temperature Distribution inside the Chip Crucible

Chip DSC Instrument



- Small Instrument, low costs
- Easy and cost effective exchange of the chip sensor -> ideal for **critical samples** (e.g. explosives, corrosive samples)
- Very Low Energy Consumption -> Control with Smart Phone/Laptop via USB port possible

Chip DSC Instrument



Available also with:

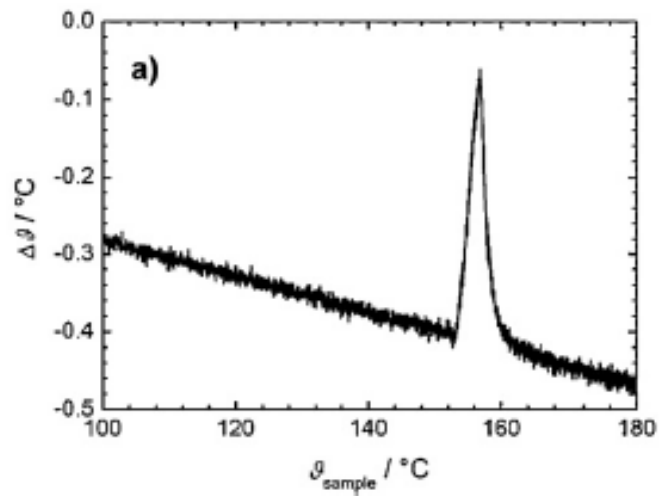
- Autosampler
- High Pressure Cell (e.g. OIT, Sorption)
- UV lamp (curing reactions)

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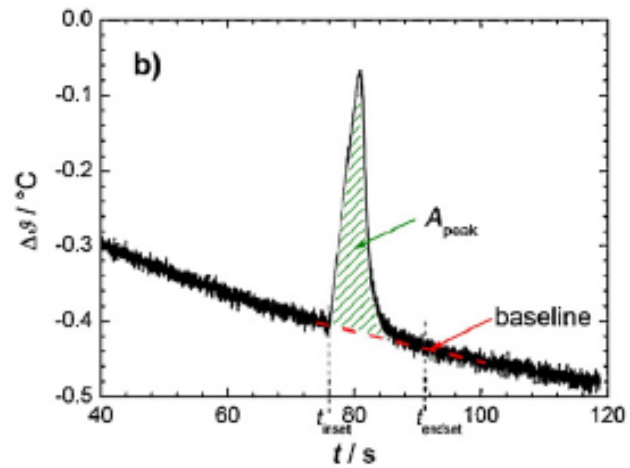
Performance Tests Chip DSC



Repeatability of Melting Peak Area

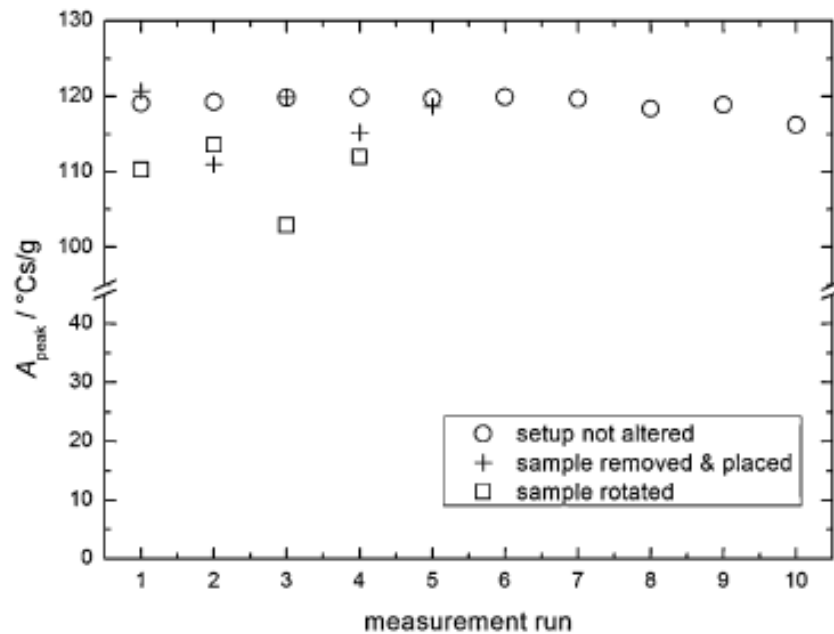


Indium Raw Signal



Calculation of Melt Peak Area

Repeatability of Melting Peak Area



10.993 mg Indium in Aluminum pan

$$R_{A,\text{peak}} = \pm \delta_{A,\text{peak}} = \frac{\bar{\sigma}_{A,\text{peak}}}{\bar{A}_{\text{peak}}} \times 100\%$$

$R_{A,\text{peak,nc}} = \pm 0.3\%$ (no change)

$R_{A,\text{peak,sc}} = \pm 1.5\%$ (sample change)

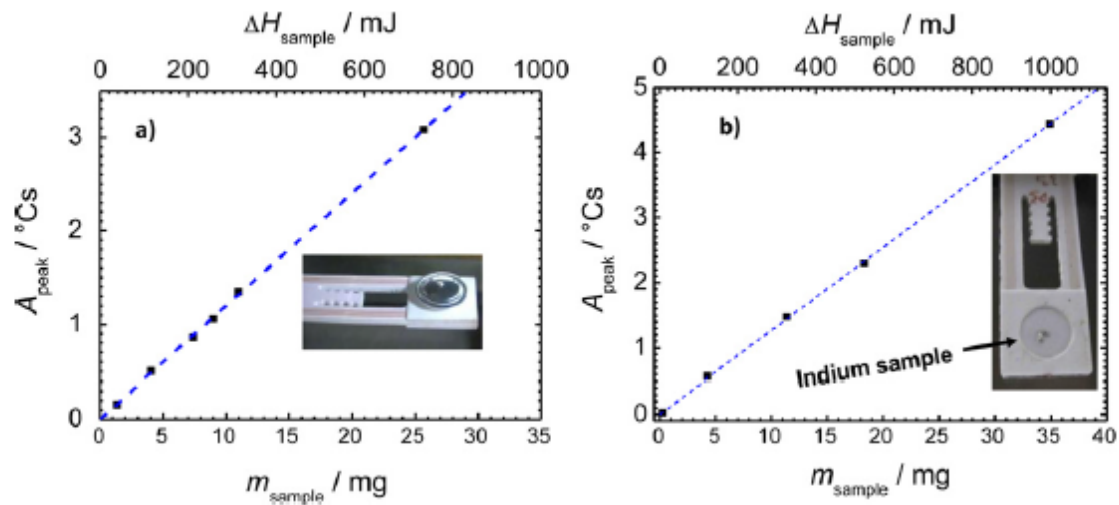
$R_{A,\text{peak,rt}} = \pm 2.2\%$ (sample position change)

-> Very good reproducibility

Sample Mass - Linearity

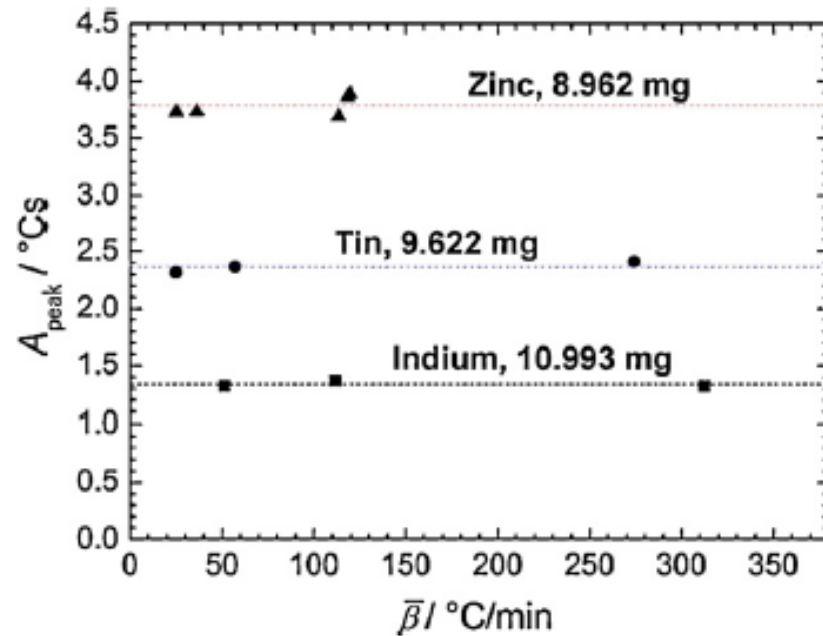
- Heat Transfer from the heater to the sample and reference ONLY through thermal conductivity
- Thermal conductivity of the chip material is balanced (glass ceramic material)-> nearly independent on temperature

-> Linearity regarding the sample mass



Melting Peak Areas vs. Sample mass

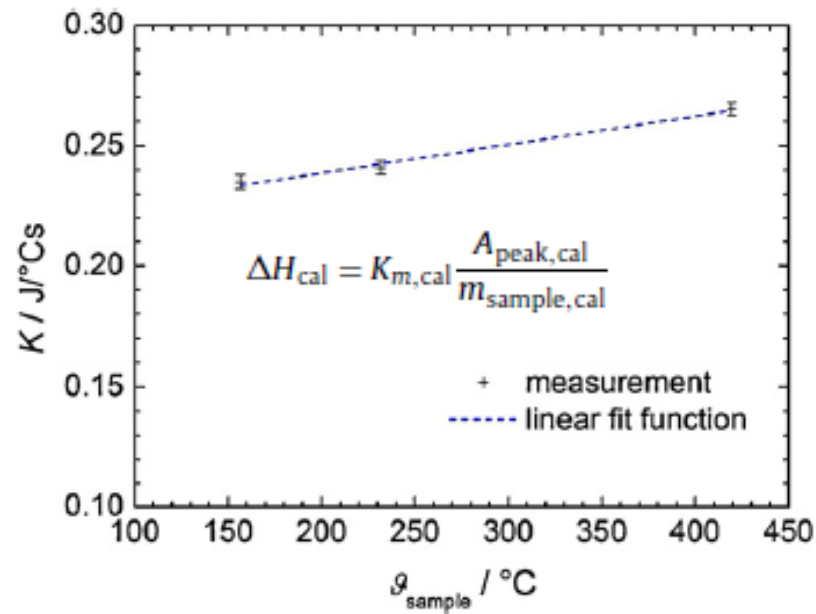
Heating Rate



Melting Peak Areas **independent** on Heating Rate (up to 320 K/min)

Melting Peak Areas vs. Heating Rate

Calorimetric Calibration



Enthalpy Conversion Factor vs. Temperature

- Indium, Tin and Zinc measurements
- Linear behavior

$$K(\vartheta_{\text{sample}}) = 0.215 \text{ J}/\text{s}^\circ\text{C} + 1.2 \times 10^{-4} \text{ J}/\text{s}^\circ\text{C}^2 \vartheta_{\text{sample}}$$

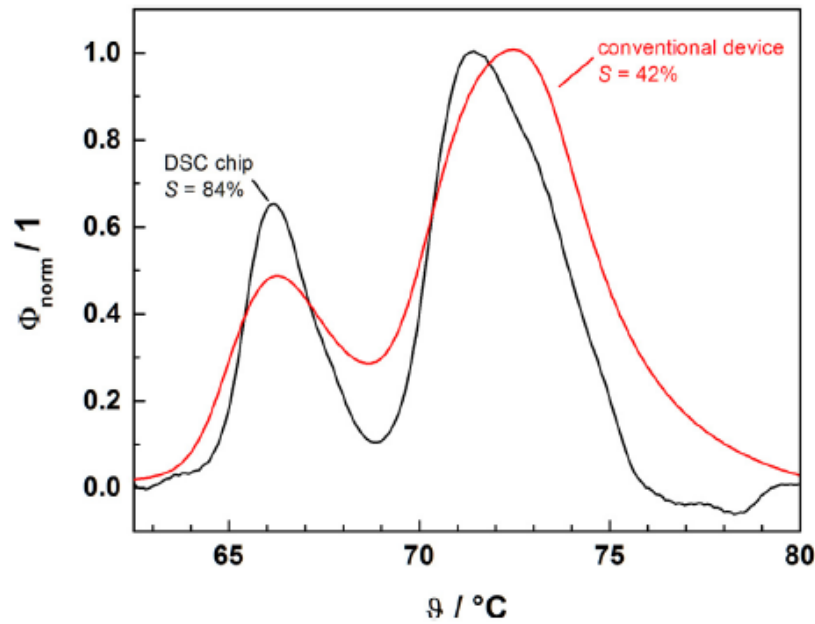
$$\Phi(\vartheta_{\text{sample}}) = K(\vartheta_{\text{sample}}) \Delta\vartheta(\vartheta_{\text{sample}})$$

- > Time saving 2 point Calibration enough
- > valid for **all** heating rates

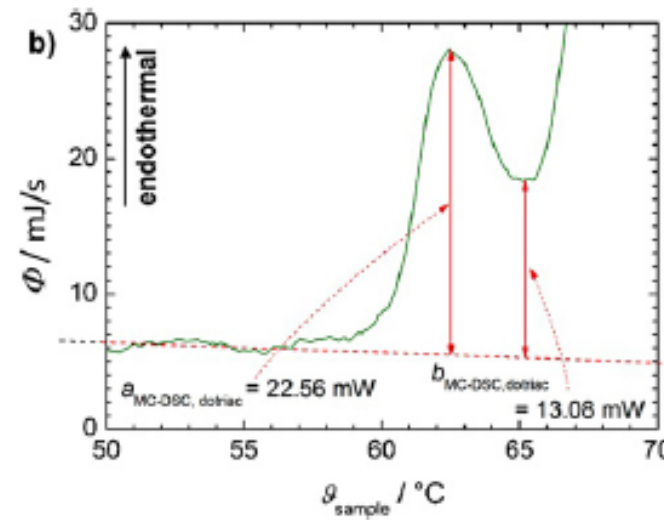
Resolution

Calculation of the Resolution Factor:

$$S = \left(1 - \frac{b}{a}\right)$$

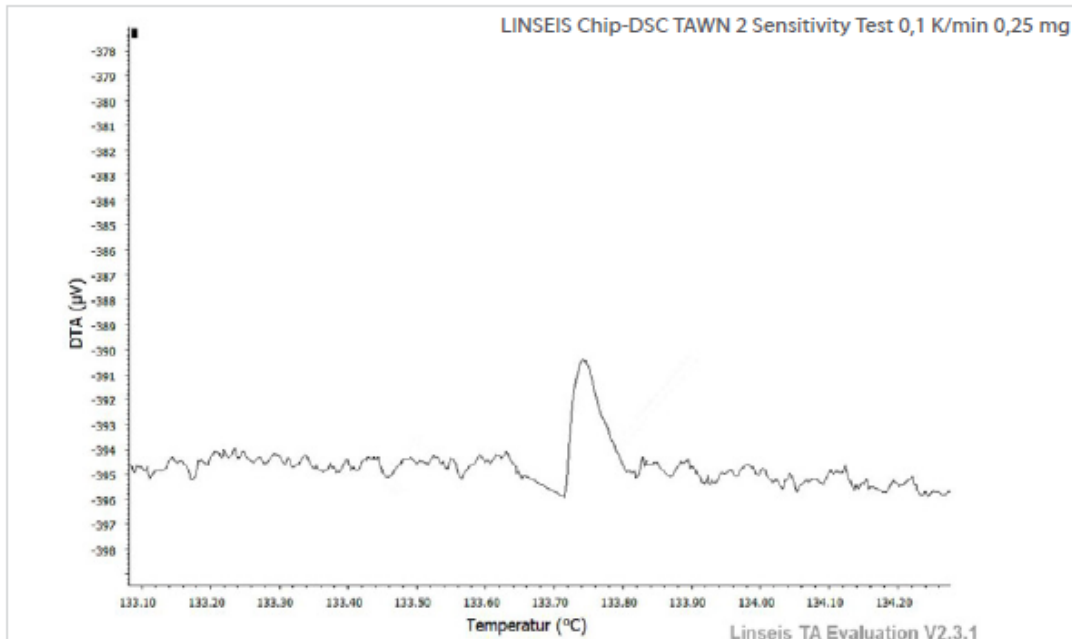


1,5 mg Dotriacontane ($\text{C}_{32}\text{H}_{66}$) – Paraffin in Aluminium Crucible



-> Better Resolution compared to conventional DSC instruments

Sensitivity



Sensitivity Factor (Peak/Noise Ratio):

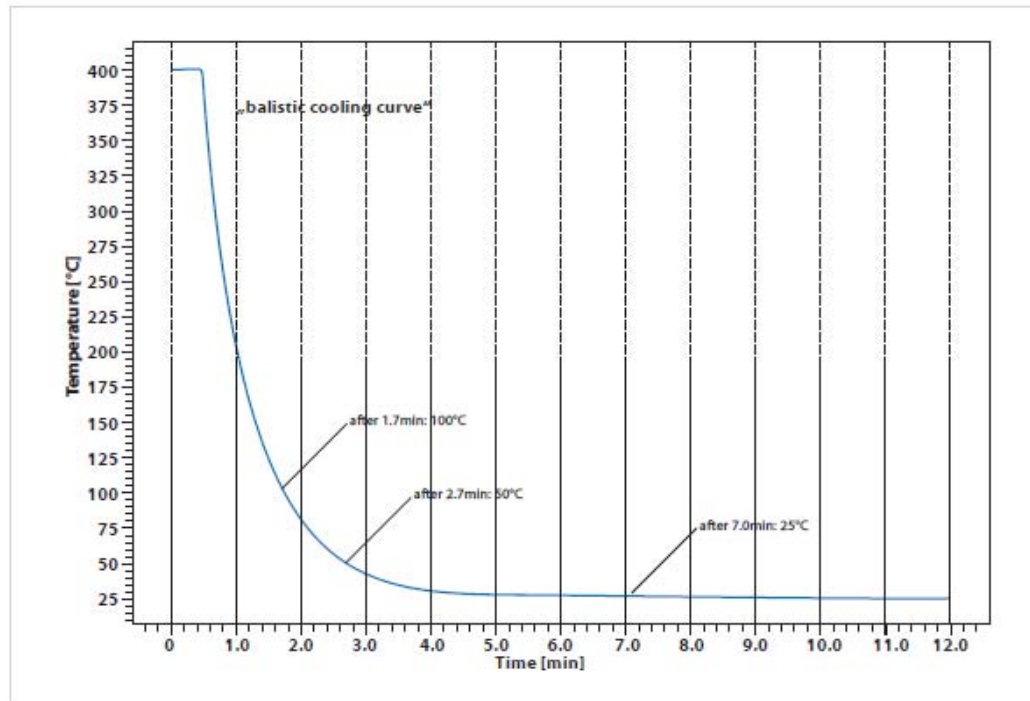
5.034

- Comparable to high end conventional DSC instruments
- Measurements at high heating rates up to 300 K/min can improve the sensitivity significantly

4,4'-Azoxyanisole – TAWN Test

Cooling

Rapid cooling rates without active cooling



Specifications

	Chip-DSC 10	Chip-DSC 100
Temperature range	-150°C (with appropriate cooling option) up to +600°C (Peltier cooling system, LN ₂ cooling system)	-180°C up to +600°C (Peltier cooling system, Closed-loop Intracooler, LN ₂ cooling system)
Heating and cooling rates	0,001 up to 200°C/min	0,001 up to 1000°C/min
Temperature accuracy	+/- 0.2K	+/- 0.2K
Temperature precision	+/- 0.02K	+/- 0.02K
Digital resolution	16.8 million points	16.8 million points
Resolution	0.03 µW	0.03 µW
Atmospheres	inert, oxidizing (static, dynamic)	inert, oxidizing (static, dynamic)

Conclusions

- Better Resolution than conventional DSC's
- Same sensitivity than conventional DSC's
- Caloric Measurements independent on heating rates
- Caloric sensitivity depends linear on sample mass
- High heating and cooling rates
- Measurements under pressure and UV- light easy to realize
- Much lower costs
- Easy and cost effective exchange of the chip (ideal for critical samples)

Thank you for your attention!

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